

## Description

The XPX80P02RX uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **General Features**

V<sub>DS</sub> = -20V I<sub>D</sub> =-80A

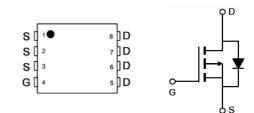
 $R_{DS(ON)} < 4m\Omega @ V_{GS}=4.5V$ 

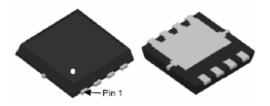
### Application

Battery protection

Load switch

Uninterruptible power supply





#### **Package Marking and Ordering Information**

Product ID	Pack	Marking	Qty(PCS)
XPX80P02RX	PDFN3*3-8L	XPX80P02RX XXX YYYY	5000
bsolute Maximu	m Ratings (Tc=25℃unless otherwise n	oted)	
Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	-20	V
VGS	Gate-Source Voltage	±12	V
I <sub>D</sub> @T <sub>C</sub> =25℃	Continuous Drain Current, $V_{GS} @$ -4.5V $^{1}$	-80	А
I₀@Tc=70℃	Continuous Drain Current, $V_{GS}$ @ -4.5V <sup>1</sup>	-44	А
IDM	Pulsed Drain Current <sup>2</sup>	-300	А
EAS	Single Pulse Avalanche Energy	180	mJ
P₀@Tc=25℃	Total Power Dissipation <sup>3</sup>	43.1	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R₀JA	Thermal Resistance Junction-Ambient <sup>1</sup>	85	°C/W
R₀JC	Thermal Resistance Junction-Case <sup>1</sup>	2.9	°C/W



#### Electrical Characteristics (TJ=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	VGS = 0V, ID = -250µA	-20	-	-	V
IGSS	Gate-body Leakage current	VDS = 0V, VGS = ±12V	-	-	±100	nA
IDSS	Zero Gate Voltage Drain Current TJ=25°C		-	-	-1	μA
IDSS	Zero Gate Voltage Drain Current TJ=100°C	VDS = -20V, VGS = 0V	-	-	-100	
VGS(th)	Gate-Threshold Voltage	VDS = VGS, ID = -250µA	-0.4	-0.7	-1.0	V
RDS(on)	Drain-Source On-Resistance4	VGS = -4.5V, ID = -10A	-	4.0	5.5	mΩ
RDS(on)	Drain-Source On-Resistance4	VGS = -2.5V, ID = -10A	-	5.0	6.8	
gfs	Forward Transconductance4	VDS = -4.5V, ID = -10A	-	56	-	S
Ciss	Input Capacitance		-	4770	-	pF
Coss	Output Capacitance	VDS = -10V, VGS =0V, f =1MHz	-	665	-	
Crss	Reverse Transfer Capacitance	1 1101112	-	570	-	
Rg	Gate Resistance	f =1MHz	-	9.6	-	Ω
Qg	Total Gate Charge		-	55	-	nC
Qgs	Gate-Source Charge	VGS = -4.5V,VDS = -10V, ID= -10A	-	5.2	-	
Qgd	Gate-Drain Charge		-	10	-	
td(on)	Turn-On Delay Time		-	22	-	
tr	Rise Time	VGS = -4.5V, VDD = -10V,	-	38	-	ns
td(off)	Turn-Off Delay Time	RG = 3Ω, ID= -10A	-	110	-	
tf	Fall Time		-	62	-	
VSD	Diode Forward Voltage4	IS = -10A, VGS = 0V	-	-	-1.2	V
IS	Continuous Source Current	TC=25°C	-	-	-70	Α

#### Note :

1. The data tested by surface mounted on a 1 inch 2  $\,$  FR-4 board with 2OZ copper.

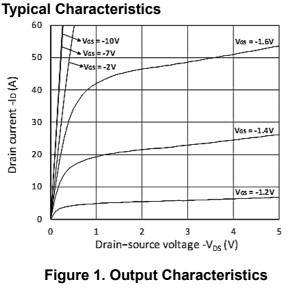
2、The EAS data shows Max. rating. The test condition is VDD=-25V, VGS=-10V, L=0.4mH, IAS = -20A.

2 、The data tested by pulsed , pulse width  $\,\leq\,$  300us , duty cycle  $\,\leq\,$  2%

 $3\.$  The power dissipation is limited by  $150\,^\circ\!\!\mathbb{C}$  junction temperature

4、 The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation.





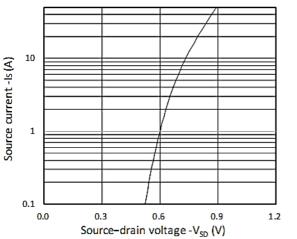


Figure 3. Forward Characteristics of Reverse

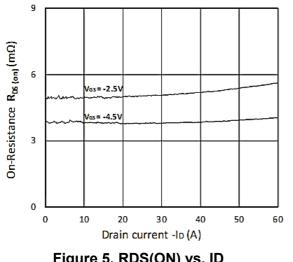
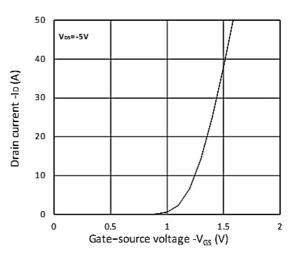
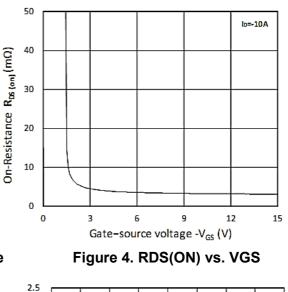
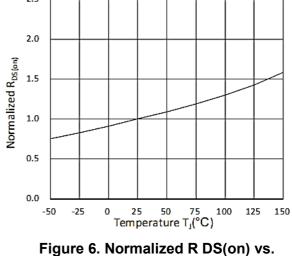


Figure 5. RDS(ON) vs. ID



**Figure 2. Transfer Characteristics** 





Temperature



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## -20V P-Channe Enhancement Mode MOSFET

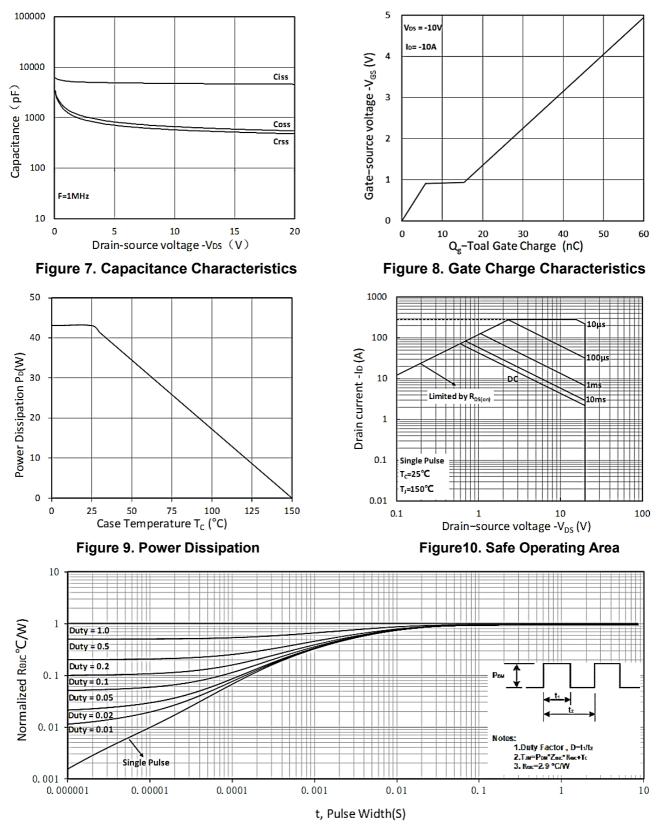
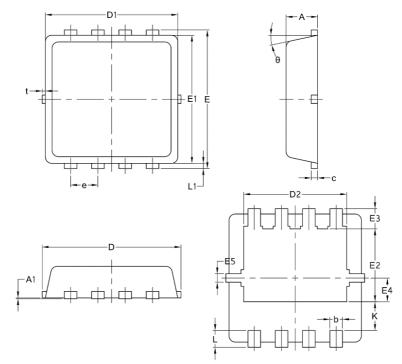


Figure 11 Normalized Maximum Transient Thermal Impedance



# Package Mechanical Data-DFN3\*3-8L-JQ Single



	Common mm			
Symbol				
	Mim	Nom	Max	
А	0.70	0.75	0.85	
A1	/	/	0.05	
b	0.20	0.30	0.40	
С	0.10	0.152	0.25	
D	3.15	3.30	3.45	
D1	3.00	3.15	3.25	
D2	2.29	2.45	2.65	
E	3.15	3.30	3.45	
E1	2.90	3.05	3.20	
E2	1.54	1.74	1.94	
E3	0.28	0.48	0.65	
E4	0.37	0.57	0.77	
E5	0.10	0.20	0.30	
е	0.60	0.65	0.70	
К	0.59	0.69	0.89	
L	0.30	0.40	0.50	
L1	0.06	0.125	0.20	
t	0	0.075	0.13	
Φ	10	12	14	



#### Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	<b>245℃</b> ± <b>5</b> ℃	5sec <del>±</del> 1sec
Pb-Free device	<b>260</b> ℃+0/-5℃	5sec±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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